

L Number	Hits	Search Text	DB	Time stamp
1	872	((charged adj particle adj beam) or CPB) and defect	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/01/27 14:26
2	0	(((charged adj particle adj beam) or CPB) and defect) and (stencil adj structure)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/01/27 14:26
3	78	(((charged adj particle adj beam) or CPB) and defect) and stencil	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/01/27 14:26
4	19	(((charged adj particle adj beam) or CPB) and defect) and stencil ) and sample	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/01/27 14:27
5	14	((((charged adj particle adj beam) or CPB) and defect) and stencil ) and sample) and (etching or etched)	USPAT; US-PGPUB; EPO; JPO; IBM_TDB	2004/01/27 14:28